

<b>Notice of References Cited</b>	Application/Control No. 09/580,793	Applicant(s)/Patent Under Reexamination PHILYAW ET AL.	
	Examiner Uyen-Chau N. Le	Art Unit 2876	Page 1 of 1

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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